

## 64-BIT HIGH WITHSTAND VOLTAGE CMOS DRIVER

### DESCRIPTION

The  $\mu$ PD16306B is a high withstand voltage CMOS driver for flat display panels such as PDP, VFD and EL. It consists of a 64-bit bi-directional shift register, a 64-bit latch and a high withstand voltage CMOS driver. The logic circuit operates on 5 V power supply (CMOS level input), so that it can be connected to a microcomputer. The driver block comprises 80 V, 50 mA MAX. high withstand voltage output buffer, and both the logic block and driver block consist of CMOS, allowing operation with low power consumption.

### FEATURES

- 64-bit bi-directional shift registers
- Data control by transfer clock (external) and latch
- High-speed data transfer:  $f_{MAX.} = 16$  MHz MIN. (in cascade connection)
- Wide operating temperature range:  $T_A = -40$  to  $+85$  °C
- High withstand voltage output: 80 V, 50 mA MAX.
- High withstand voltage Full CMOS process
- Polarities of all drivers can be reversed by using /PC pin.

**Remark** /xxx indicates active low signal.

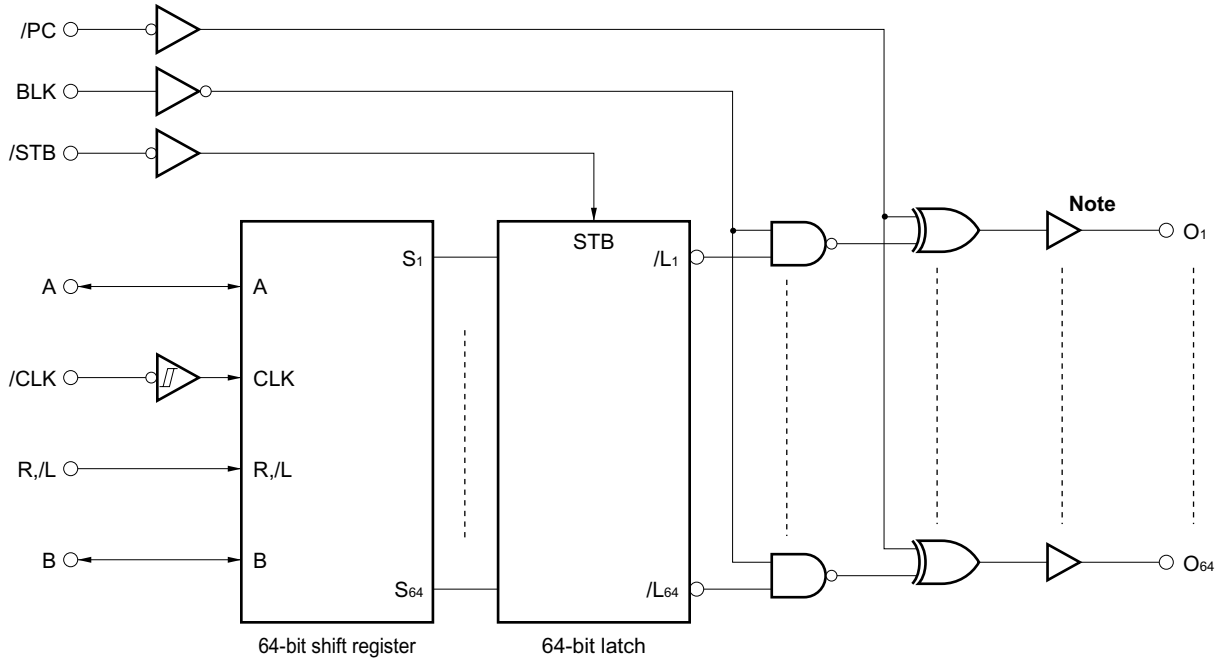
### ORDERING INFORMATION

Part Number	Package
$\mu$ PD16306BGF-3BA	100-pin plastic QFP (14 x 20)

The information in this document is subject to change without notice. Before using this document, please confirm that this is the latest version.

Not all products and/or types are available in every country. Please check with an NEC Electronics sales representative for availability and additional information.

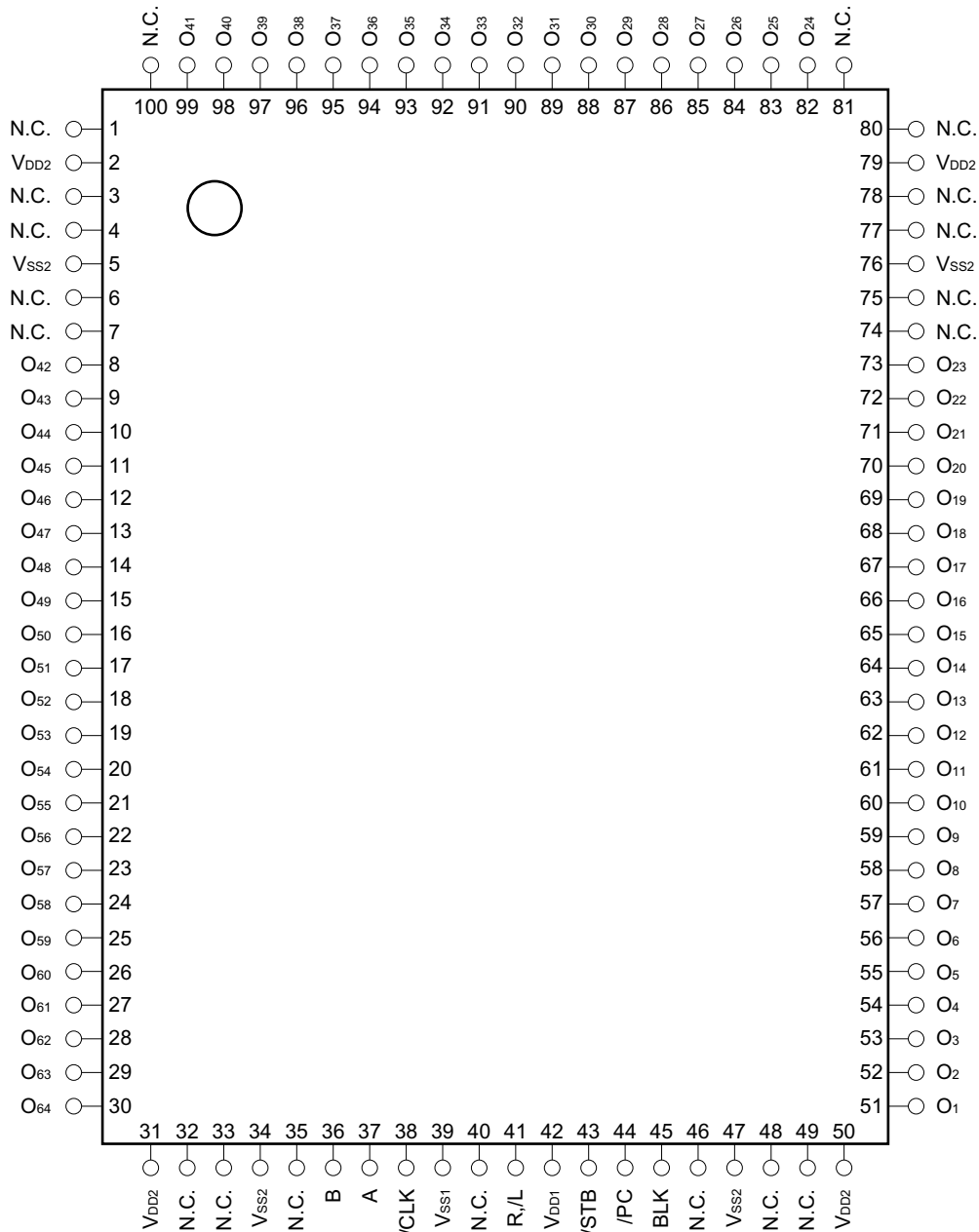
1. BLOCK DIAGRAM



**Note** High withstand voltage CMOS drivers (80 V, ±50 mA MAX.)

2. PIN CONFIGURATION (Top View)

μPD16306BGF-3BA: 100-pin plastic QFP (14 x 20)



- Cautions**
1. Be sure to leave pin 40 open because it is connected to the lead frame.
  2. Be sure to use all the VDD1, VDD2, VSS1 and VSS2 pins. Keep the VSS1 and VSS2 pins at the same voltage level.
  3. Supply power to VDD1, logic inputs and VDD2 in this order to protect the device from destruction due to latch up. Turn off power in the reverse order.  
Observe these power sequences even during a transition period.
  4. Since the μPD16306B have a CMOS structure, be careful about electrical static destruction.

3. PIN FUNCTIONS

Pin Symbol	Pin Name	I/O	Remark
/PC	Polarity reverse	Input	/PC = L: Reverses polarities of all outputs
BLK	Blank	Input	BLK = H: All outputs = H or L
/STB	Latch strobe	Input	Through at L, holds data at H
A	RIGHT data	I/O	R <sub>i</sub> /L = H: A input, B output
B	LEFT data	I/O	R <sub>i</sub> /L = L: B input, A output
/CLK	Clock	Input	Executes shift at falling edge
R <sub>i</sub> /L	Shift direction control	Input	Right shift mode at H: A → O <sub>1</sub> ...O <sub>64</sub> → B Left shift mode at L: B → O <sub>64</sub> ...O <sub>1</sub> → A
O <sub>1</sub> to O <sub>64</sub>	High withstand voltage output	Output	80 V, 50 mA MAX.
V <sub>DD1</sub>	Logic power supply	–	5 V ± 10%
V <sub>DD2</sub>	Driver power supply	–	10 to 70 V
V <sub>SS1</sub>	Logic ground	–	Connected to GND of system
V <sub>SS2</sub>	Power ground	–	Connected to GND of system
N.C.	Non connection	–	No connection. Be sure to leave pin 40 open.

4. TRUTH TABLE

Shift Register

Input		I/O		Shift Register
R <sub>v</sub> /L	/CLK	A	B	
H	↓	Input	Output <sup>Note1</sup>	Right shift
H	H or L		Output	Hold
L	↓	Output <sup>Note2</sup>	Input	Left shift
L	H or L	Output		Hold

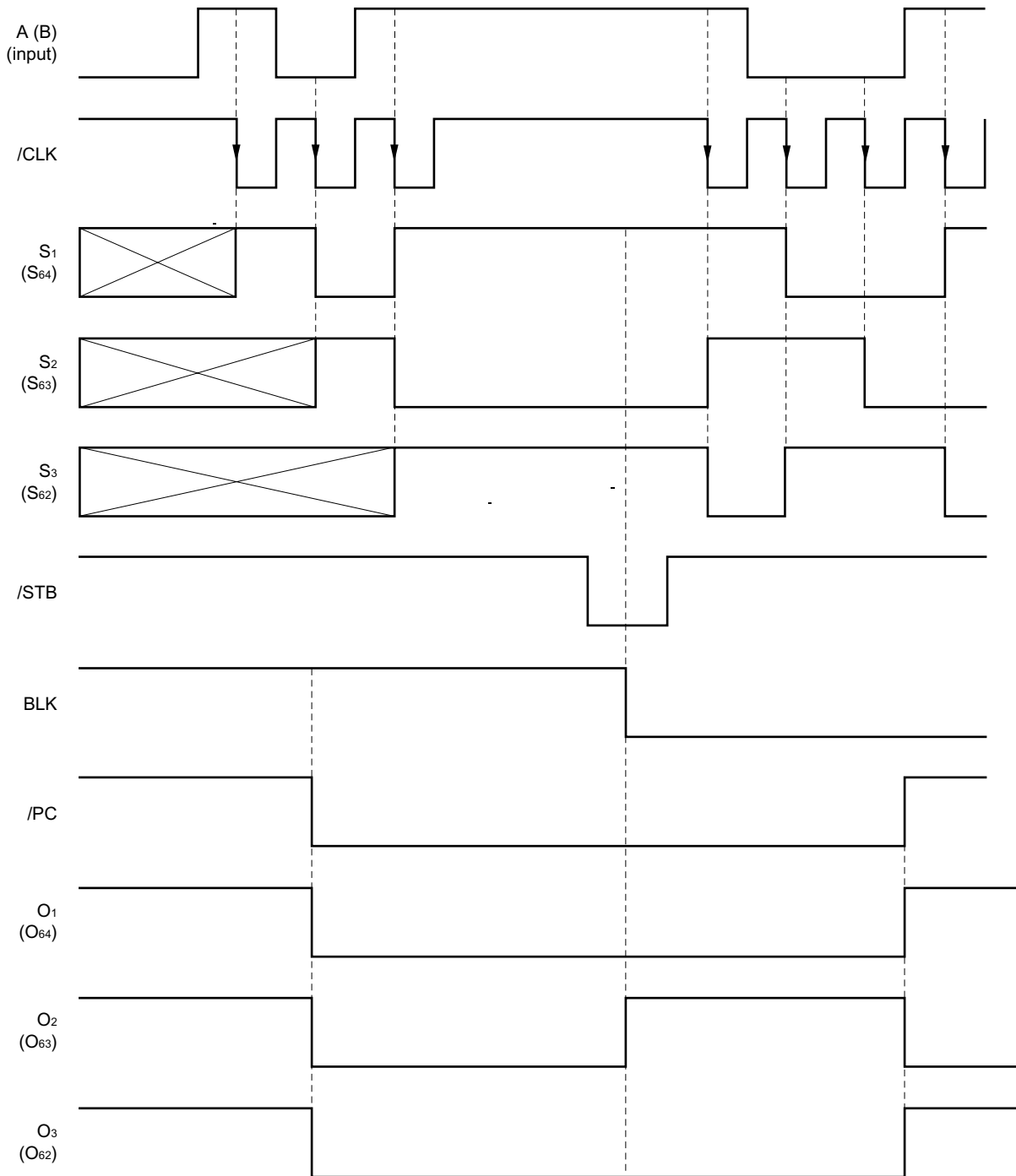
- Notes**
1. S<sub>63</sub> is shifted to the position of S<sub>64</sub> and output from B at the falling edge of the clock.
  2. S<sub>2</sub> is shifted to the position of S<sub>1</sub> and output from A at the falling edge of the clock.

Latch and Driver

Input				Driver Output Stage
A (B)	/STB	BLK	/PC	
X	X	H	H	H (All driver outputs are H.)
X	X	H	L	L (All driver outputs are L.)
H	L	L	H	H
H	L	L	L	L
L	L	L	H	L
L	L	L	L	H
X	H	L	H	Outputs data immediately before the /STB goes to H.
X	H	L	L	Reverses and outputs data immediately before the /STB goes to H.

**Remark** X = H or L, H = high level, L = low level

5. TIMING CHART



Remark ( ): R,/L = L

6. ELECTRICAL SPECIFICATIONS

**Absolute Maximum Ratings (T<sub>A</sub> = 25°C, V<sub>SS1</sub> = V<sub>SS2</sub> = 0 V)**

Parameter	Symbol	Rating	Unit
Logic supply voltage	V <sub>DD1</sub>	-0.5 to +7.0	V
Logic input voltage	V <sub>I1</sub>	-0.5 to V <sub>DD1</sub> + 0.5	V
Logic output voltage	V <sub>O1</sub>	-0.5 to V <sub>DD1</sub> + 0.5	V
Driver supply voltage	V <sub>DD2</sub>	-0.5 to +80	V
Driver output voltage	V <sub>O2</sub>	-0.5 to V <sub>DD2</sub> + 0.5	V
Driver output current	I <sub>O2</sub>	±50	mA
Power dissipation	P <sub>D</sub>	1000	mW
Operating ambient temperature	T <sub>A</sub>	-40 to +85	°C
Storage temperature	T <sub>stg</sub>	-65 to +150	°C

**Caution** Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

**Recommended Operating Range (T<sub>A</sub> = -40 to +85°C, V<sub>SS1</sub> = V<sub>SS2</sub> = 0 V)**

Parameter	Symbol	MIN.	TYP.	MAX.	Unit
Logic supply voltage	V <sub>DD1</sub>	4.5	5.0	5.5	V
High-level input voltage	V <sub>IH</sub>	0.7 V <sub>DD1</sub>		V <sub>DD1</sub>	V
Low-level input voltage	V <sub>IL</sub>	0		0.2 V <sub>DD1</sub>	V
Driver supply voltage	V <sub>DD2</sub>	10		70	V
Driver output current	I <sub>OL2</sub>			+40	mA
	I <sub>OH2</sub>			-40	mA

**Electrical Characteristics (T<sub>A</sub> = 25°C, V<sub>DD1</sub> = 5.0 V, V<sub>DD2</sub> = 70 V, V<sub>SS1</sub> = V<sub>SS2</sub> = 0 V)**

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
High-level output voltage	V <sub>OH1</sub>	Logic I <sub>OH1</sub> = -1.0 mA	0.9 V <sub>DD1</sub>			V
Low-level output voltage	V <sub>OL1</sub>	Logic I <sub>OL1</sub> = 1.0 mA			0.1 V <sub>DD1</sub>	V
High-level output voltage	V <sub>OH21</sub>	O <sub>1</sub> to O <sub>64</sub> , I <sub>OH2</sub> = -1.0 mA	69			V
	V <sub>OH22</sub>	O <sub>1</sub> to O <sub>64</sub> , I <sub>OH2</sub> = -10.0 mA	65			V
Low-level output voltage	V <sub>OL21</sub>	O <sub>1</sub> to O <sub>64</sub> , I <sub>OL2</sub> = 5.0 mA			1.0	V
	V <sub>OL22</sub>	O <sub>1</sub> to O <sub>64</sub> , I <sub>OL2</sub> = 40.0 mA			10	V
High-level input voltage	V <sub>IH</sub>	Logic	0.7 V <sub>DD1</sub>			V
Low-level input voltage	V <sub>IL</sub>	Logic			0.2 V <sub>DD1</sub>	V
High-level input current	I <sub>IH</sub>	V <sub>i</sub> = V <sub>DD1</sub>			1.0	μA
Low-level input current	I <sub>IL</sub>	V <sub>i</sub> = 0 V			-1.0	μA
Static current dissipation	I <sub>DD11</sub>	Logic, T <sub>A</sub> = 25°C			10	μA
	I <sub>DD12</sub>	Logic, T <sub>A</sub> = -40 to +85°C			100	μA
	I <sub>DD21</sub>	Driver, T <sub>A</sub> = 25°C			100	μA
	I <sub>DD22</sub>	Driver, T <sub>A</sub> = -40 to +85°C			1000	μA

**Switching Characteristics (T<sub>A</sub> = 25°C, V<sub>DD1</sub> = 5.0 V, V<sub>DD2</sub> = 70 V, V<sub>SS1</sub> = V<sub>SS2</sub> = 0 V, Logic: C<sub>L</sub> = 15 pF, Driver: C<sub>L</sub> = 50 pF)**

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Propagation delay time	t <sub>PHL1</sub>	/CLK → A/B			50	ns
	t <sub>PLH1</sub>				50	ns
	t <sub>PHL2</sub>	/CLK → O <sub>1</sub> to O <sub>64</sub>			160	ns
	t <sub>PLH2</sub>				160	ns
	t <sub>PHL3</sub>	/STB → O <sub>1</sub> to O <sub>64</sub>			150	ns
	t <sub>PLH3</sub>				150	ns
	t <sub>PHL4</sub>	BLK → O <sub>1</sub> to O <sub>64</sub>			145	ns
	t <sub>PLH4</sub>				145	ns
	t <sub>PHL5</sub>	/PC → O <sub>1</sub> to O <sub>64</sub>			140	ns
t <sub>PLH5</sub>				140	ns	
Rise time	t <sub>TLH</sub>	O <sub>1</sub> to O <sub>64</sub>			100	ns
Fall time	t <sub>THL</sub>	O <sub>1</sub> to O <sub>64</sub>			100	ns
Maximum clock frequency	f <sub>MAX.</sub>	Duty = 50%, data loading	20			MHz
		In cascade connection	16			MHz
Input capacitance	C <sub>i</sub>				20	pF

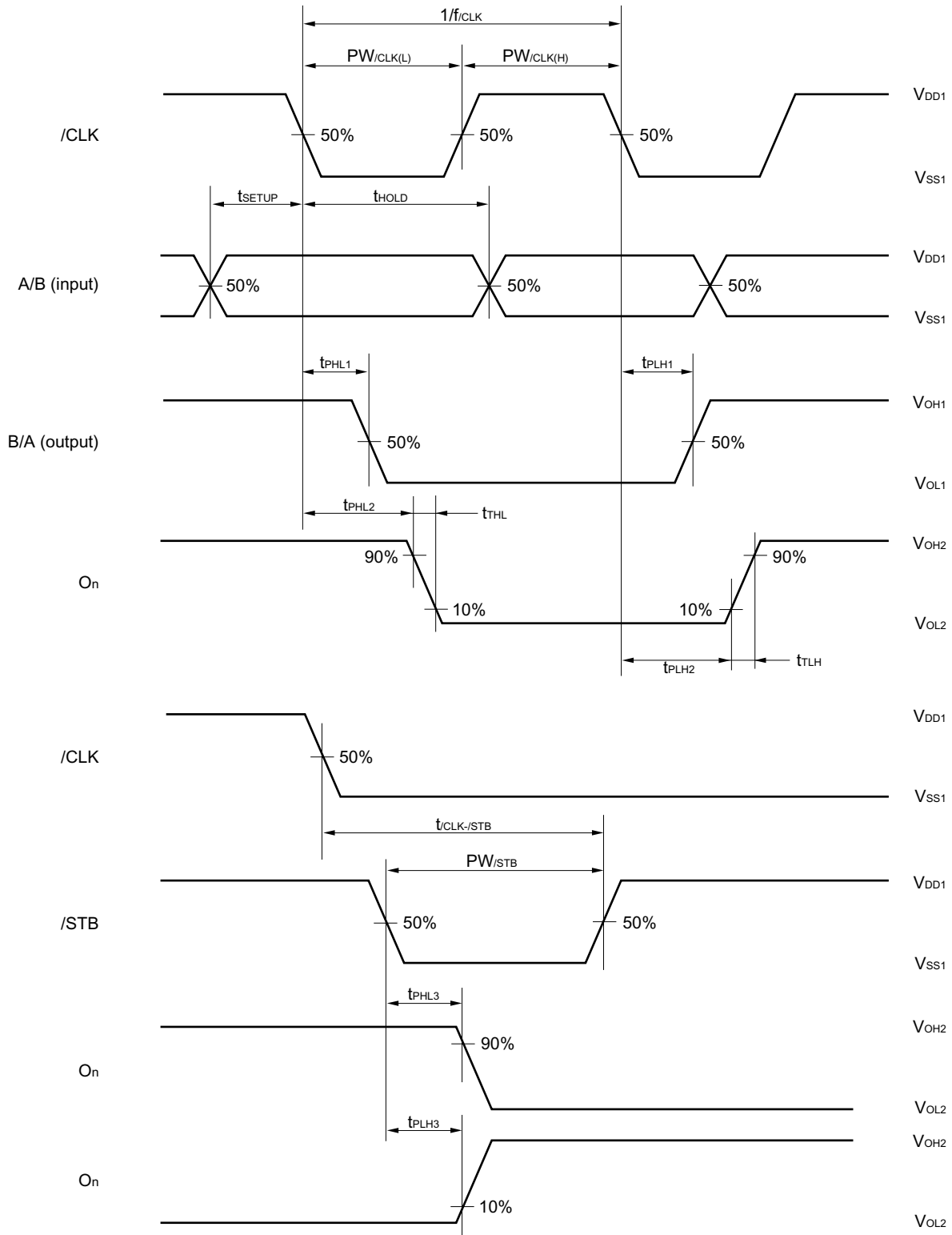


**Timing Requirements ( $T_A = -40$  to  $+85^\circ\text{C}$ ,  $V_{DD1} = 4.5$  to  $5.5$  V,  $V_{SS1} = V_{SS2} = 0$  V)**

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Clock pulse width	$PW_{/CLK(L)}$ , $PW_{/CLK(H)}$		20			ns
Strobe pulse width	$PW_{/STB}$		20			ns
Blank pulse width	$PW_{BLK}$		200			ns
/PC pulse width	$PW_{/PC}$		200			ns
Data setup time	$t_{SETUP}$		10			ns
Data hold time	$t_{HOLD}$		10			ns
Clock-strobe time	$t_{CLK/STB}$	/CLK ↓ → /STB ↑	50			ns

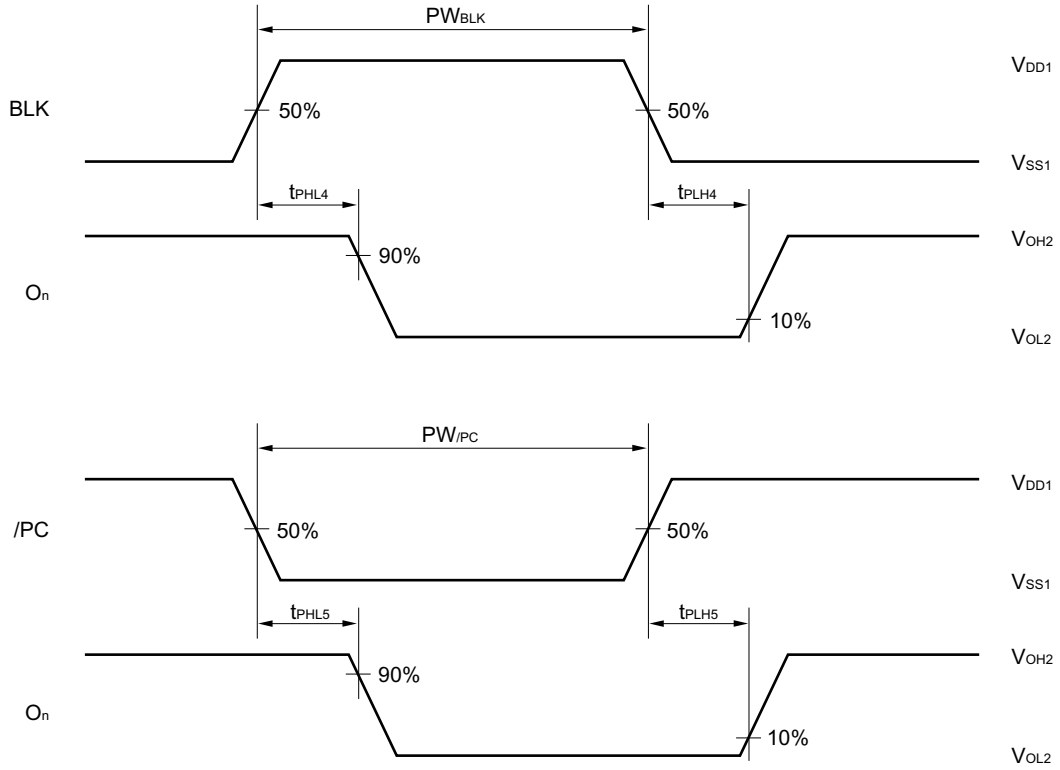
Switching Characteristics Waveforms (1/2)

Unless otherwise specified,  $V_{IH} = V_{IL} = 0.5 V_{DD1}$ .



Switching Characteristics Waveforms (2/2)

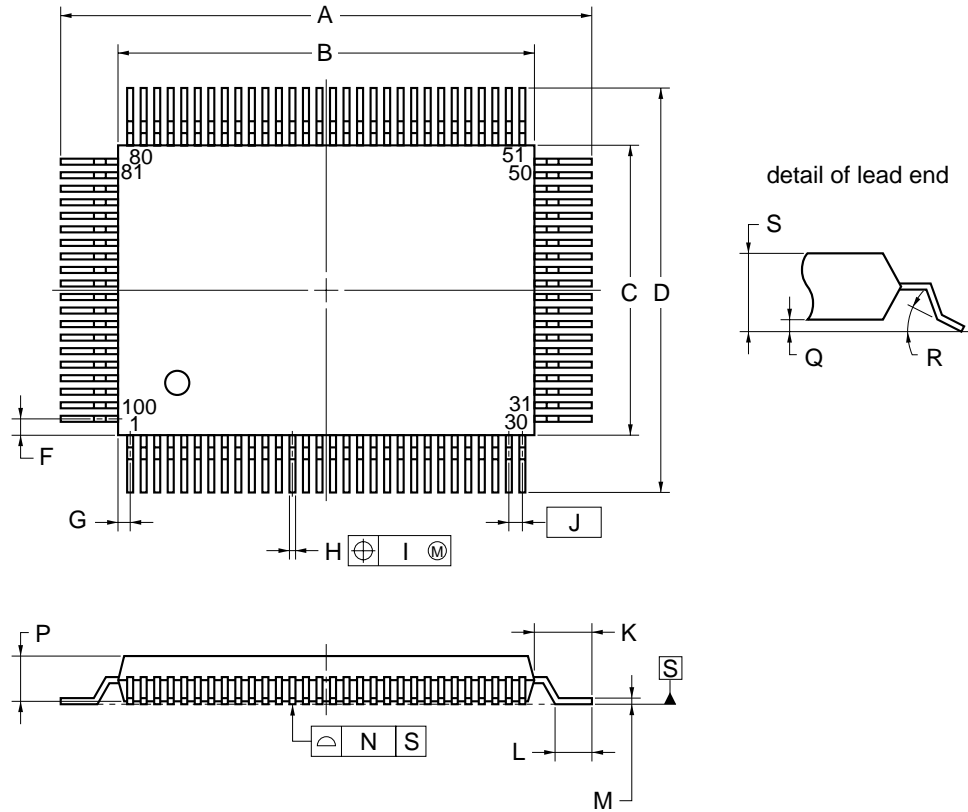
Unless otherwise specified,  $V_{IH} = V_{IL} = 0.5 V_{DD1}$ .



★ 7. PACKAGE DRAWING

μPD16306BGF-3BA

100-PIN PLASTIC QFP (14x20)



NOTE

Each lead centerline is located within 0.15 mm of its true position (T.P.) at maximum material condition.

ITEM	MILLIMETERS
A	23.6±0.4
B	20.0±0.2
C	14.0±0.2
D	17.6±0.4
F	0.8
G	0.6
H	0.30±0.10
I	0.15
J	0.65 (T.P.)
K	1.8±0.2
L	0.8±0.2
M	0.15 <sup>+0.10</sup> / <sub>-0.05</sub>
N	0.10
P	2.7
Q	0.1±0.1
R	5°±5°
S	3.0 MAX.

P100GF-65-3BA-4

★ 8. RECOMMENDED SOLDERING CONDITIONS

The following conditions must be met for soldering conditions of the μ PD16306B.

For more details, refer to the **Semiconductor Device Mounting Technology Manual (C10535E)**.

Please consult with our sales offices in case other soldering process is used, or in case the soldering is done under different conditions.

**Type of Surface Mount Device**

**μPD16306BGF-3BA: 100-pin plastic QFP (14 x 20)**

Soldering Process	Soldering Conditions	Symbol
Infrared ray reflow	Peak temperature of package surface: 235°C or below, Reflow time: 30 seconds or below (210°C or higher), Number of reflow processes: MAX. 3	IR35-00-3
VPS	Peak temperature of package surface: 215°C or below, Reflow time: 40 seconds or below (200°C or higher), Number of reflow processes: MAX. 1	VP15-00-1
Partial heating method	Terminal temperature: 300°C or below, Time: 3 seconds or below (Per one side of the device).	—

**Caution** Do not apply more than one soldering method at any one time, except for the partial heating method.

[MEMO]

**NOTES FOR CMOS DEVICES****① PRECAUTION AGAINST ESD FOR SEMICONDUCTORS**

Note:

Strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred. Environmental control must be adequate. When it is dry, humidifier should be used. It is recommended to avoid using insulators that easily build static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work bench and floor should be grounded. The operator should be grounded using wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with semiconductor devices on it.

**② HANDLING OF UNUSED INPUT PINS FOR CMOS**

Note:

No connection for CMOS device inputs can be cause of malfunction. If no connection is provided to the input pins, it is possible that an internal input level may be generated due to noise, etc., hence causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using a pull-up or pull-down circuitry. Each unused pin should be connected to  $V_{DD}$  or GND with a resistor, if it is considered to have a possibility of being an output pin. All handling related to the unused pins must be judged device by device and related specifications governing the devices.

**③ STATUS BEFORE INITIALIZATION OF MOS DEVICES**

Note:

Power-on does not necessarily define initial status of MOS device. Production process of MOS does not define the initial operation status of the device. Immediately after the power source is turned ON, the devices with reset function have not yet been initialized. Hence, power-on does not guarantee out-pin levels, I/O settings or contents of registers. Device is not initialized until the reset signal is received. Reset operation must be executed immediately after power-on for devices having reset function.

**Reference Documents**

**NEC Semiconductor Device Reliability/Quality Control System (C10983E)**  
**Quality Grades On NEC Semiconductor Devices (C11531E)**

- **The information in this document is current as of January, 2003. The information is subject to change without notice. For actual design-in, refer to the latest publications of NEC Electronics data sheets or data books, etc., for the most up-to-date specifications of NEC Electronics products. Not all products and/or types are available in every country. Please check with an NEC Electronics sales representative for availability and additional information.**
- No part of this document may be copied or reproduced in any form or by any means without the prior written consent of NEC Electronics. NEC Electronics assumes no responsibility for any errors that may appear in this document.
- NEC Electronics does not assume any liability for infringement of patents, copyrights or other intellectual property rights of third parties by or arising from the use of NEC Electronics products listed in this document or any other liability arising from the use of such products. No license, express, implied or otherwise, is granted under any patents, copyrights or other intellectual property rights of NEC Electronics or others.
- Descriptions of circuits, software and other related information in this document are provided for illustrative purposes in semiconductor product operation and application examples. The incorporation of these circuits, software and information in the design of a customer's equipment shall be done under the full responsibility of the customer. NEC Electronics assumes no responsibility for any losses incurred by customers or third parties arising from the use of these circuits, software and information.
- While NEC Electronics endeavors to enhance the quality, reliability and safety of NEC Electronics products, customers agree and acknowledge that the possibility of defects thereof cannot be eliminated entirely. To minimize risks of damage to property or injury (including death) to persons arising from defects in NEC Electronics products, customers must incorporate sufficient safety measures in their design, such as redundancy, fire-containment and anti-failure features.
- NEC Electronics products are classified into the following three quality grades: "Standard", "Special" and "Specific".

The "Specific" quality grade applies only to NEC Electronics products developed based on a customer-designated "quality assurance program" for a specific application. The recommended applications of an NEC Electronics product depend on its quality grade, as indicated below. Customers must check the quality grade of each NEC Electronics product before using it in a particular application.

"Standard": Computers, office equipment, communications equipment, test and measurement equipment, audio and visual equipment, home electronic appliances, machine tools, personal electronic equipment and industrial robots.

"Special": Transportation equipment (automobiles, trains, ships, etc.), traffic control systems, anti-disaster systems, anti-crime systems, safety equipment and medical equipment (not specifically designed for life support).

"Specific": Aircraft, aerospace equipment, submersible repeaters, nuclear reactor control systems, life support systems and medical equipment for life support, etc.

The quality grade of NEC Electronics products is "Standard" unless otherwise expressly specified in NEC Electronics data sheets or data books, etc. If customers wish to use NEC Electronics products in applications not intended by NEC Electronics, they must contact an NEC Electronics sales representative in advance to determine NEC Electronics' willingness to support a given application.

(Note)

- (1) "NEC Electronics" as used in this statement means NEC Electronics Corporation and also includes its majority-owned subsidiaries.
- (2) "NEC Electronics products" means any product developed or manufactured by or for NEC Electronics (as defined above).